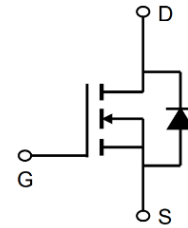


## 60V N-Channel Enhancement Mode MOSFET

### Description

The AP20N06S uses advanced trench technology to provide excellent  $R_{DS(ON)}$ , low gate charge and operation with gate voltages as low as 10V. This device is suitable for use as a

Battery protection or in other Switching application.



### General Features

$V_{DS} = 60V$   $I_D = 20A$

$R_{DS(ON)} < 10m\Omega$  @  $V_{GS}=10V$  (Type: 7.8m $\Omega$ )

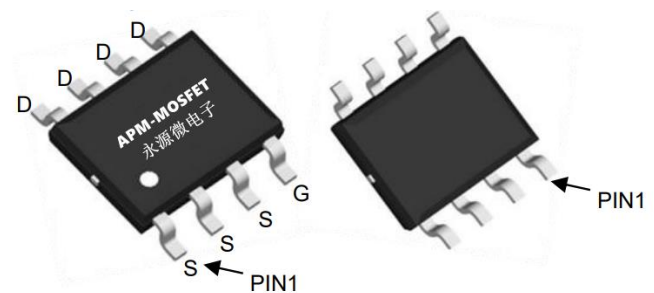


### Application

Battery protection

Load switch

synchronous rectification



### Package Marking and Ordering Information

Product ID	Pack	Marking	Qty(PCS)
AP20N06S	SOP-8L	AP20N06S XXX YYYYY	3000

### Absolute Maximum Ratings ( $T_c=25^\circ C$ unless otherwise noted)

Symbol	Parameter	Rating	Units
V <sub>DS</sub>	Drain-Source Voltage	60	V
V <sub>GS</sub>	Gate-Source Voltage	±20	V
$I_{D@T_c=25^\circ C}$	Continuous Drain Current, $V_{GS} @ 10V^1$	20	A
$I_{D@T_c=100^\circ C}$	Continuous Drain Current, $V_{GS} @ 10V^1$	13	A
IDM	Pulsed Drain Current <sup>2</sup>	80	A
EAS	Single Pulse Avalanche Energy <sup>3</sup>	140	mJ
$P_D@T_c=25^\circ C$	Total Power Dissipation <sup>4</sup>	116	W
TSTG	Storage Temperature Range	-55 to 150	°C
T <sub>J</sub>	Operating Junction Temperature Range	-55 to 150	°C
R <sub>θJA</sub>	Thermal Resistance Junction-ambient <sup>1</sup>	46	°C/W
R <sub>θJC</sub>	Thermal Resistance Junction-Case <sup>1</sup>	0.85	°C/W

## 60V N-Channel Enhancement Mode MOSFET

### Electrical Characteristics (T<sub>J</sub>=25°C, unless otherwise noted)

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
BVDSS	Drain-Source Breakdown Voltage	V <sub>GS</sub> =0V, I <sub>D</sub> =250uA	68	72	---	V
ΔBVDSS/ΔT <sub>J</sub>	BVDSS Temperature Coefficient	Reference to 25°C, I <sub>D</sub> =1mA	---	0.023	---	V/°C
RDS(ON)	Static Drain-Source On-Resistance <sup>2</sup>	V <sub>GS</sub> =10V, I <sub>D</sub> =10A	---	7.8	10	mΩ
VGS(th)	Gate Threshold Voltage	V <sub>GS</sub> =V <sub>DS</sub> , I <sub>D</sub> =250uA	2.0	3.0	4.0	V
ΔVGS(th)	VGS(th) Temperature Coefficient		---	-4.2	---	mV/°C
IDSS	Drain-Source Leakage Current	V <sub>DS</sub> =24V, V <sub>GS</sub> =0V, T <sub>J</sub> =25°C	---	---	1	uA
		V <sub>DS</sub> =24V, V <sub>GS</sub> =0V, T <sub>J</sub> =55°C	---	---	5	
IGSS	Gate-Source Leakage Current	V <sub>GS</sub> =±20V, V <sub>DS</sub> =0V	---	---	±100	nA
gfs	Forward Transconductance	V <sub>DS</sub> =5V, I <sub>D</sub> =10A	---	5.5	---	S
R <sub>g</sub>	Gate Resistance	V <sub>DS</sub> =0V, V <sub>GS</sub> =0V, f=1MHz	---	2.3	---	Ω
Q <sub>g</sub>	Total Gate Charge (4.5V)	V <sub>DS</sub> =30V, I <sub>D</sub> =20A, V <sub>GS</sub> =10V	---	35	---	nC
Q <sub>gs</sub>	Gate-Source Charge		---	11	---	
Q <sub>gd</sub>	Gate-Drain Charge		---	9	---	
Td(on)	Turn-On Delay Time	V <sub>DS</sub> =30V, I <sub>D</sub> =20A, R <sub>GEN</sub> =6Ω, V <sub>GS</sub> =10V	---	15	---	ns
T <sub>r</sub>	Rise Time		---	94	---	
Td(off)	Turn-Off Delay Time		---	46	---	
T <sub>f</sub>	Fall Time		---	32	---	
Ciss	Input Capacitance	V <sub>DS</sub> =15V, V <sub>GS</sub> =0V, f=1MHz	---	4062	---	pF
Coss	Output Capacitance		---	261	---	
Crss	Reverse Transfer Capacitance		---	231	---	
IS	Continuous Source Current <sup>1,5</sup>	V <sub>G</sub> =V <sub>D</sub> =0V, Force Current	---	---	80	A
ISM	Pulsed Source Current <sup>2,5</sup>		---	---	320	A
VSD	Diode Forward Voltage <sup>2</sup>	V <sub>GS</sub> =0V, I <sub>S</sub> =80A	---	---	1.2	V
trr	Reverse Recovery Time	T <sub>J</sub> =25°C I <sub>F</sub> =20A, dI/dt=100A/μs	---	78	---	nS
Q <sub>rr</sub>	Reverse Recovery Charge		---	51	---	nC

#### Note :

- 1、 The data tested by surface mounted on a 1 inch<sup>2</sup>FR-4 board with 20Z copper.
- 2、 The data tested by pulsed , pulse width .The EAS data shows Max. rating .
- 3、 The power dissipation is limited by 175°C junction temperature
- 4、 The data is theoretically the same as ID and IDM , in real applications , should be limited by total power dissipation.

**Typical Characteristics**

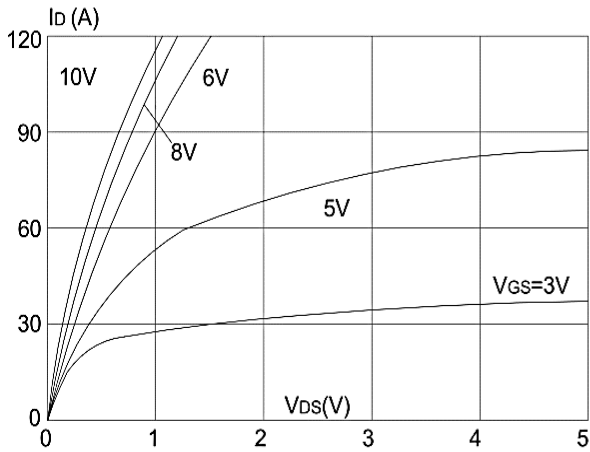


Figure 1: Output Characteristics

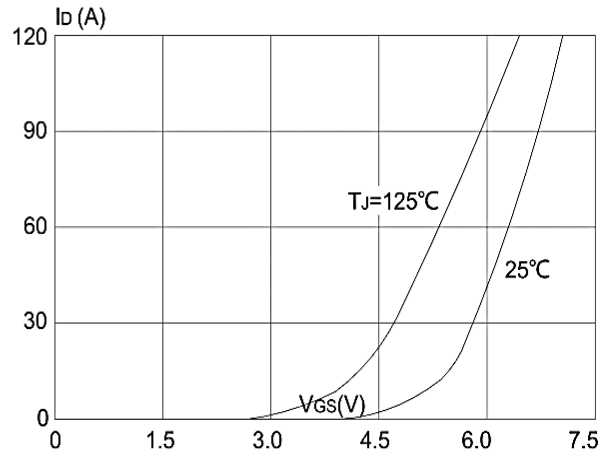


Figure 2: Typical Transfer Characteristics

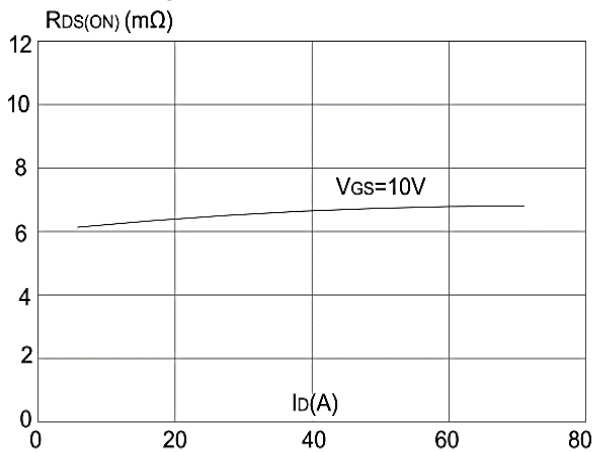


Figure 3: On-resistance vs. Drain Current

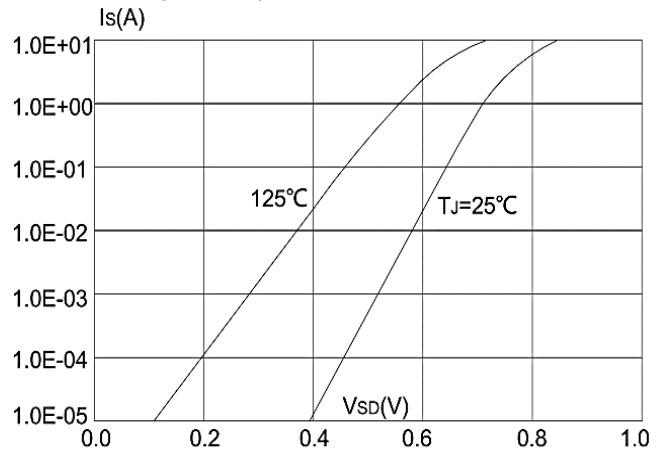


Figure 4: Body Diode Characteristics

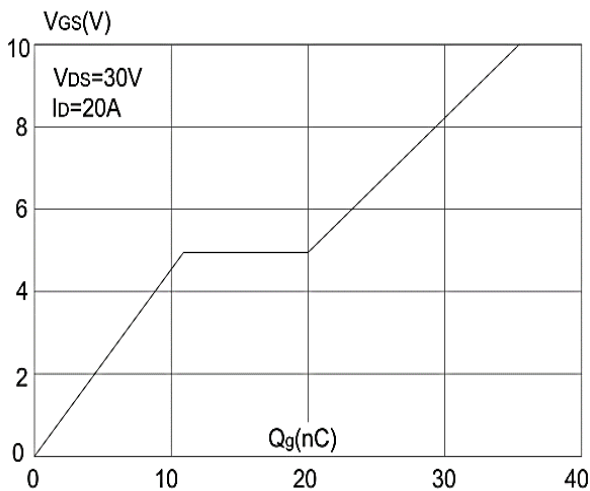


Figure 5: Gate Charge Characteristics

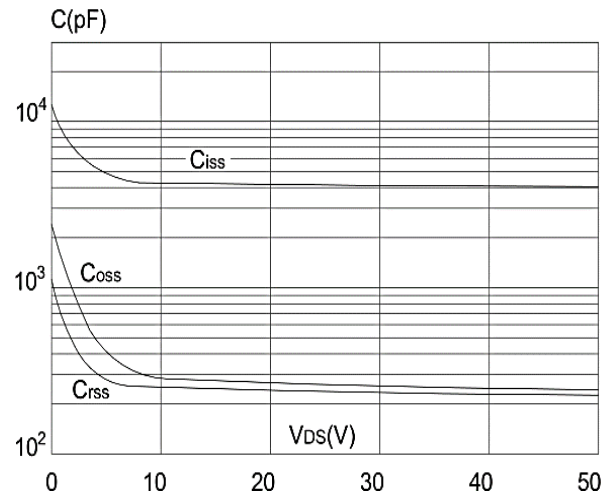
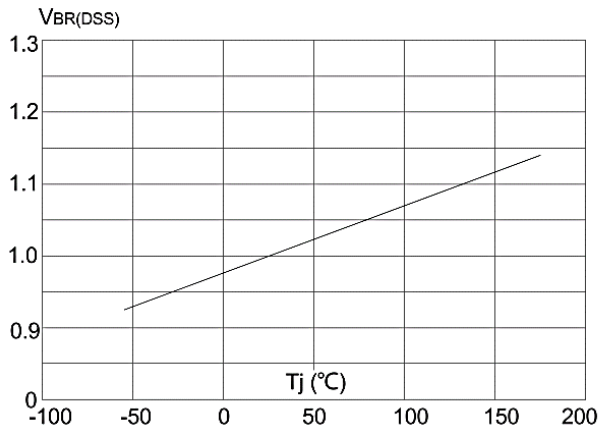


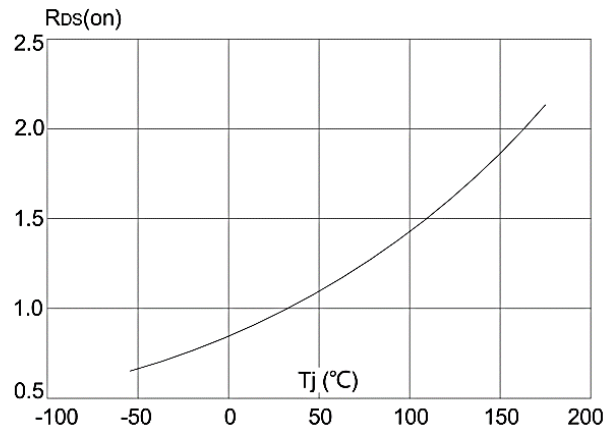
Figure 6: Capacitance Characteristics



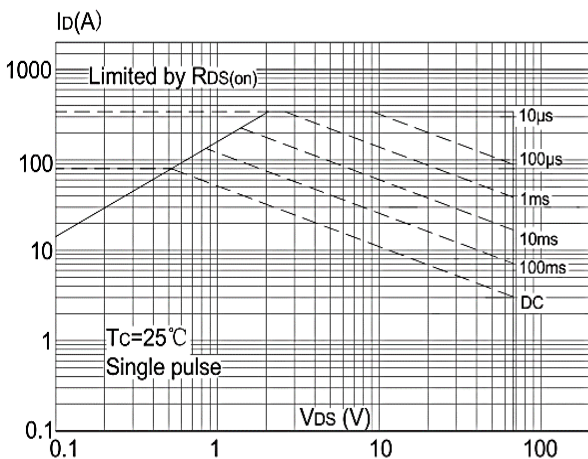
## 60V N-Channel Enhancement Mode MOSFET



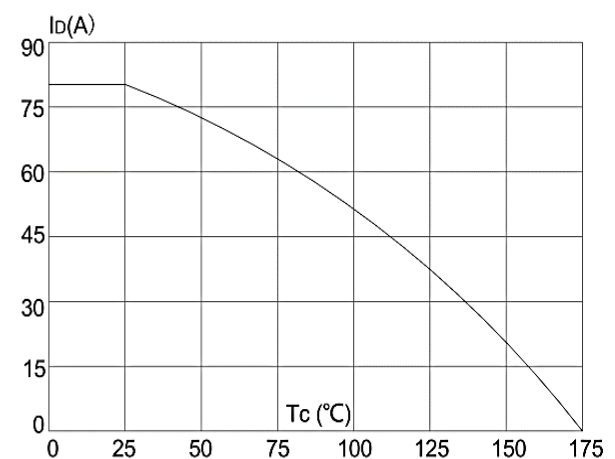
**Figure 7: Normalized Breakdown Voltage vs. Junction Temperature**



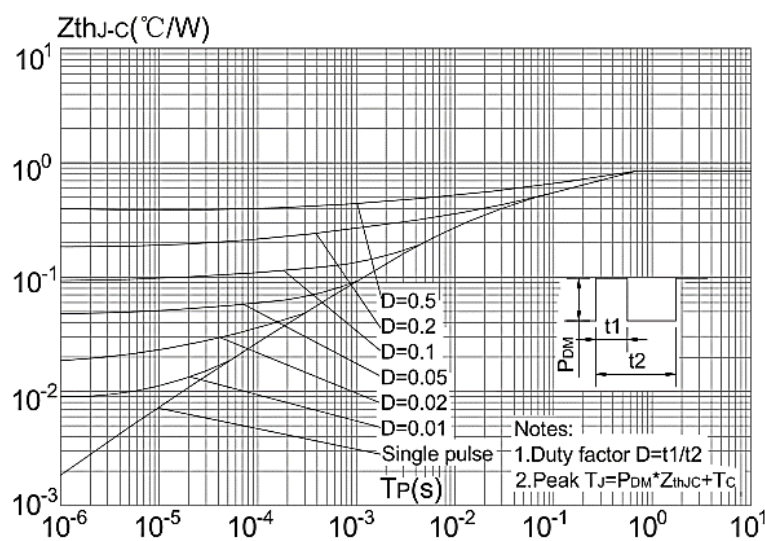
**Figure 8: Normalized on Resistance vs. Junction Temperature**



**Figure 9: Maximum Safe Operating Area**

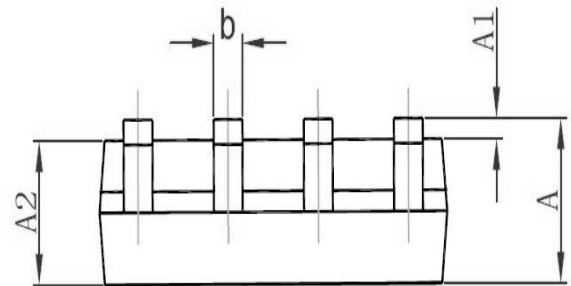
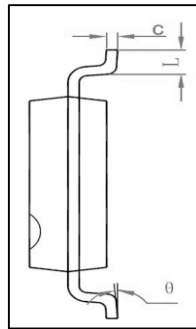
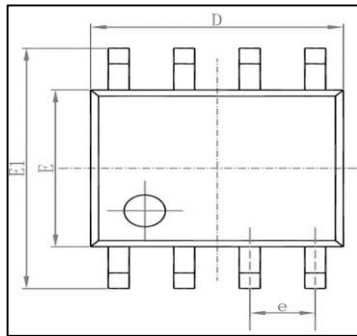


**Figure 10: Maximum Continuous Drain Current vs. Ambient Temperature**

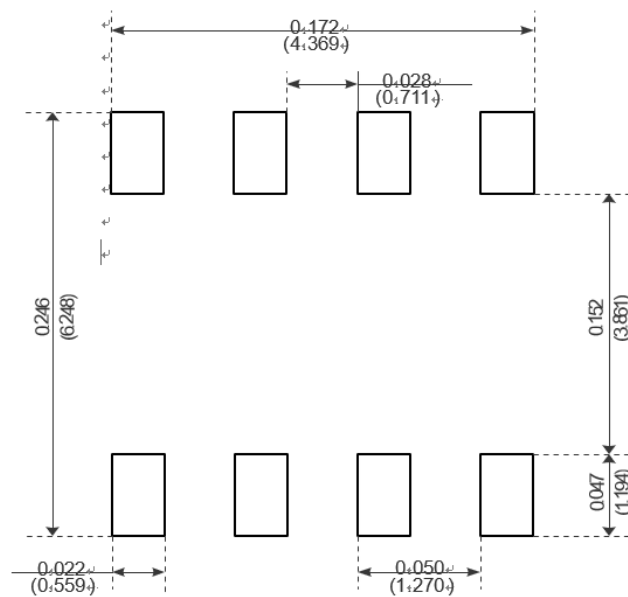


**Figure.11: Maximum Effective Transient Thermal Impedance, Junction-to-Ambien**

### Package Mechanical Data-SOP-8L



Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min	Max	Min	Max
A	1.350	1.750	0.053	0.069
A1	0.100	0.250	0.004	0.010
A2	1.350	1.550	0.053	0.061
b	0.330	0.510	0.013	0.020
c	0.170	0.250	0.006	0.010
D	4.700	5.100	0.185	0.200
E	3.800	4.000	0.150	0.157
E1	5.800	6.200	0.228	0.244
e	1.270 (BSC)		0.050 (BSC)	
L	0.400	1.270	0.016	0.050
θ	0°	8°	0°	8°



Recommended Minimum Pads

**60V N-Channel Enhancement Mode MOSFET****Attention**

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**60V N-Channel Enhancement Mode MOSFET**

Edition	Date	Change
RVE1.0	2020/12/21	Initial release

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